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[\[PDF \(750K\)\]](#) [\[References\]](#)**A Study of the Cascade Auger Process Using a Cluster Calculation**[Sei FUKUSHIMA](#)¹⁾²⁾ and [Satoshi OTA](#)²⁾*1) Advanced Surface Chemical Analysis Group, Advanced Nano Characterization Center, National Institute for Materials Science**2) Materials Analysis Station, Department of Materials Infrastructure, National Institute for Materials Science***(Received August 5, 2009)****(Accepted December 5, 2009)**

The Auger process on shallow levels, caused by the Auger process in deeper levels, called "cascade Auger process", were studied. From the measurement result, the cascade Auger process can be clearly observed by the excitation of X-ray tubes instead of a synchrotron radiation source. Applying a theoretical investigation with a cluster calculation to the spectral change of the Ag $M_{VI,V}VV$ peak, it was theoretically shown that the cascade Auger process should be correct for explaining the observed spectral change. In addition, it pointed out the existence of a cascade Auger process caused by holes left by the Coster-Kronig process on deeper levels. For the first time the measurement of this process was successful using X-ray tube excitation.

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